

**Search Notes**

Application/Control No.

10/660,671

Examiner

Daniel Pan

Applicant(s)/Patent under  
Reexamination

NGUYEN ET AL.

Art Unit

2183

**SEARCHED**

Class	Subclass	Date	Examiner
712	23 239	8/17/2006	DP

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
712	23 239	8/17/2006	DP
interference searched on west PGP		8/17/2006	DP

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
west ppg uspat jpoabs derwent ibm ieee npl 711/213 predict jump 712/235 mult. way 712/213,41 decod. RISC	8/17/2006	DP

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